DATE Best Paper Awards

Each year the Design, Automation and Test in Europe Conference presents awards to the authors of the best papers. The selection is performed by an award committee, based on the results of the reviewing process and the quality of the final paper.

The DATE 2014 best papers are:

D Track
MAY-HAPPEN-IN-PARALLEL ANALYSIS BASED ON SEGMENT GRAPHS FOR SAFE ESL MODELS
Weiwei Chen, Xu Han, Rainer Dömer,
Center for Embedded Computer Systems, University of California, Irvine, USA

A Track
AN EFFICIENT RELIABLE PUF-BASED CRYPTOGRAPHIC KEY GENERATOR IN 65NM CMOS
Mudit Bhargava, Ken Mai,
Department of Electrical and Computer Engineering, Carnegie Mellon University, USA

T Track:
EFFICIENT SMT-BASED ATPG FOR INTERCONNECT OPEN DEFECTS
Dominik Erb, Karsten Scheibler, Matthias Sauer, Bernd Becker,
University of Freiburg, Germany

E Track
SCALABILITY BOTTLENECKS DISCOVERY IN MPSOC PLATFORMS USING DATA MINING ON SIMULATION TRACES
Sofiane Lagraa¹², Alexandre Termier¹ and Frédéric Pétrot²
¹LIG Laboratory, University Joseph Fourier, Grenoble, France;
²TIMA Laboratory, Grenoble Institute of Technology, Grenoble, France

Congratulations to the winners!